

## SECOND INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Sheep E

**Complete if Known**

<b>Application Number</b>	09/508,430
<b>Filing Date</b>	March 13, 2000
<b>First Named Inventor</b>	Meier, Rudolf et. al.
<b>Examiner Name</b>	H. Akhavannik
<b>Attorney Docket Number</b>	030705-164

## U.S. PATENT DOCUMENTS

[illegible]

## FOREIGN PATENT DOCUMENTS

[illegible]

## NON-PATENT LITERATURE DOCUMENTS

Examiner Initials	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
S.N	B. Nickolay, et al., "Automatic Textile Inspection", Studie fur die Textilindustrie, 60 pages, June 1993
J	E. Ersü, et al., "Rationelle 100% Optische Kontrolle in Der Vlies – Und Textilstoffproduktion", ISRA Systemtechnik GmbH, 16 pages
↓	Ferdinand van der Heijden, "Statistical Pattern Classification and Parameter Estimation", Image Based Measurement Systems, Object Recognition and Parameter Estimation, John Wiley & Sons, 1994

Examiner Signature	B. Nakhiwan	Date Considered	6-28-03
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

SHEET 1 OF 1

**EXAMINER:** Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.